

ARPA/NBS Workshop V, Moisture Measurement Technology for Hermetic Semiconductor Devices, 1978

Session I Mass Spectrometer Measurements

Mass Spectrometer Measurements at RADC

By Benjamin A. Moore (Rome Air Development Center) - Published in RL/NIST Moisture Workshop 1978, P3

A Method for Measuring the PPM Moisture-Sensing Limitations of Mass Spectrometers in Testing Small Packages

By Jonhny L. Hartley (Sandia Laboratories) - Published in RL/NIST Moisture Workshop 1978, P24

A Dynamic Method of Calibrating a Mass Spectrometer Used for Measuring the Water Content of Semiconductor Encapsulations

By Robert P. Merrett (British Post Office Research Centre) - Published in RL/NIST Moisture Workshop 1978, P33

Moisture Measurement by Mass Spectrometer

By John C. Pernicka (Pernicka Corporation) - Published in RL/NIST Moisture Workshop 1978, P42

Microcircuit Package Gas Analysis

By Ray F. Haack and Alex Shumka (Jet Propulsion Laboratory) - Published in RL/NIST Moisture Workshop 1978, P43

Comparison Of Mass Spectrometric Moisture Measurements by Different Laboratories

By Kenneth L. Perkins (Rockwell International) - Published in RL/NIST Moisture Workshop 1978, P58

Session II Moisture Sensors

The Effects of Assembly Techniques Upon the Performance Characteristics of Al₂O₃ In-Situ Moisture Sensors

By Victor Fong (Panametrics, Inc.) - Published in RL/NIST Moisture Workshop 1978, P69

Application Considerations of Solid State Moisture Chips for Hybrids and Associated Calibration Measurement Techniques

By Paul F. Bennowitz (Thunder Scientific Corporation) - Published in RL/NIST Moisture Workshop 1978, P75

Hysteresis and Long-Term Repeatability of Aluminium Oxide Humidity Sensors

By Herbert L. Webster (Sandia Laboratories) - Published in RL/NIST Moisture Workshop 1978, P80

Moisture Standards and Sensors

By Charles G. Messenger (Rome Air Development Center) - Published in RL/NIST Moisture Workshop 1978, P82

Assessment of the Use of Measurement of Surface Conductivity as a Means of Determining Moisture Content of Hermetic Semiconductor Encapsulations

By Robert P. Merrett and Steven P. Sim (British Post Office Research Centre) - Published in RL/NIST Moisture Workshop 1978, P94

Moisture Sensing With the Charge-Flow Transistor

By Stephen D. Senturia, Michel G. Huberman, Robert Van der Klott (Massachusetts Institute of Technology) - Published in RL/NIST Moisture Workshop 1978, P108

A Surface Conductance Technique for the Evaluation of Internal Package Environments

By Colin W. T. Knight, Abe Korgav, and Emil Pierron (Advanced Micro Devices) - Published in RL/NIST Moisture Workshop 1978, P115

Panel Meetings

Discussion Group Summary of Mass Spectrometer

By Robert W. Thomas, Chairman (Rome Air Development Center) - Published in RL/NIST Moisture Workshop 1978, P122

Comments on Round-Robin Results

By Robert W. Thomas, Chairman (Rome Air Development Center) - Published in RL/NIST Moisture Workshop 1978, P124

Moisture Sensors

By Saburo Hasegawa, Chairman (National Bureau of Standards) - Published in RL/NIST Moisture Workshop 1978, P126

Session III Package Analysis and Quality Assurance

Parts-Per-Million Water-Vapor Generating System Used to Simulate Moisture in Small Integrated Circuit Packages

By Jonhny L. Hartley (Sandia Laboratories) - Published in RL/NIST Moisture Workshop 1978, P128

A Total Moisture Analyser for Hermetic Devices

By Steven R. Loucks and Arthur W. Burnham (Medtronic Inc.) - Published in RL/NIST Moisture Workshop 1978, P133

Analysis of Water Vapor in Purified Gas Systems

By Haiping Dun, Brenton L. Mattes, and David A. Stevenson (Stanford University) - Published in RL/NIST Moisture Workshop 1978, P143

Mass Spectrometric Moisture Analysis of Hermetic Semiconductor Devices by Acetylene Conversion

By William M. Hickam and William R. Morgan (Westinghouse Research and Development Center) - Published in RL/NIST Moisture Workshop 1978, P153

Moisture in Packages - A User's Viewpoint

By Aaron Der Marderosian (Raytheon Company) - Published in RL/NIST Moisture Workshop 1978, P159

Problems in Specifying and Measuring Moisture Content Within Electronic Devices

By Robert W. Thomas, Chairman (Rome Air Development Center) - Published in RL/NIST Moisture Workshop 1978, P179